# X2PT IGBT Chip

XYS

<ul> <li>short circuit rated for 10 µsec.</li> <li>improved trade-off</li> <li>low switching losses</li> <li>low EMI</li> <li>Thin wafer technology combined with the &gt;</li> </ul>	• W	r-conditioning systems elding equipment		
results in a competitive low Vce(sat) Mechanical Parameters	4			
Mechanica Farameters				
Parameters	Conditions		Ratings	Unit
Area active			193.4	mm²
Area total			224.46	mm²
Wafer size Ø			150	mm
Thickness			130	μm
Material	Si	Orientation	<100>	, , , ,
Max. possible chips	per wafer		46	1 1 1 1
Passivation	front side		SiN	1 1 1 1
Metalization	top side		AlSi	
	backside		Al / Ti / Ni / Ag	1 1 1 1
Recom. wire bonds (AI)	Emitter	Number / Ø	18 / 380	- / µm
	Gate	Number / Ø	1 / 380	- / µm
Reject Ink Dot Size	Ø		0.4-1.0	mm
Recom. Storage Environment	in orig. container, in dry	v nitrogen	< 6	month

Applications:

Solar inverter

AC motor drives

Medical equipment

Uninterruptible power supply

### Terms Conditions of usage

The data contained in this product data sheet is exclusively intended for technically trained staff. The user will have to evaluate the suitability of the product for the intended application and the completeness of the product data with respect to his application. The specifications of our components may not be considered as an assurance of component characteristics. Should you require product information in excess of the data given in this product data sheet or which concerns the specific application of our product, please contact the sales office, which is responsible for you. Due to technical requirements our product may contain dangerous substances. For information on the types in question please contact the sales office, which is responsible for you.

Should you intend to use the Product in aviation applications, in health or live endangering or life support applications, please notify. For any such applications we urgently recommend

- to perform joint Risk and Quality Assessments;

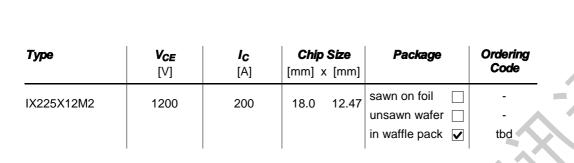
- the conclusion of Quality Agreements;

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- to establish joint measures of an ongoing product survey, and that we may make delivery depended on the realization of any such measures

# IX225X12M2

tentative



## Features / Advantages:

## • Tvjm = 175°C

- · Easy paralleling due to the positive temperature coefficient of the on-state voltage
- Rugged X2PT design (2nd generation Xtreme light Punch Through)

Parameters	Conditions		Ratings	Unit
Area active			193.4	mm²
Area total			224.46	mm²
Wafer size Ø			150	mm
Thickness			130	μm
Material	Si	Orientation	<100>	1
Max. possible chips	per wafer		46	
Passivation	front side		SiN	
Metalization	top side		AlSi	
	backside		Al / Ti / Ni / Ag	
Recom. wire bonds (Al)	Emitter	Number / Ø	18 / 380	- / µm
	Gate	Number / Ø	1 / 380	- / µm
Reject Ink Dot Size	Ø		0.4-1.0	mm
Recom. Storage Environment	in orig. container, in dry nitrogen		< 6	month
	Storage Temperature (Tstg)		-40 40	°C
Virtual junction temperature T <sub>vJ</sub>			-40 175	°C

# LIXYS

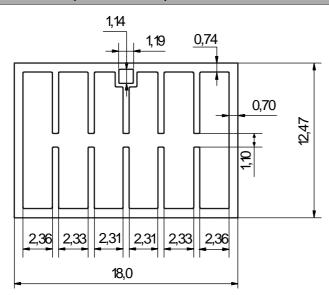
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tentative

## **Electrical Parameters**

					F	Ratings	5	11
Symbol	Definition	Conditions			min.	typ.	max.	Unit
V <sub>CES</sub>	Collector emitter voltage	$V_{GE} = 0 V$	$I_c = 1 \text{ mA}$	$T_{VJ} = 25^{\circ}C$			1200	V
V <sub>GES</sub>	Maximum DC gate voltage					7	±20	V
lc	Collector current (depending on the	rmal properties of	f assembly)			200		Α
V <sub>CE set</sub>	Collector emitter saturation voltage	$V_{GE} = 15 \text{ V}$	I <sub>c</sub> = 200 A	$T_{VJ} = 25^{\circ}C$		1.7	2	V
				$T_{vJ} = 150^{\circ}C$		2		V
V <sub>to</sub>	Threshold voltage	V <sub>GE</sub> = 15 V;	T <sub>vj</sub> = 175°C	•			1.2	V
r,	(for power loss calculation)						5.8	mΩ
I <sub>ces</sub>	Collector emitter leakage current	$V_{ce} = 1200 V$	$V_{GE} = 0 V$	$T_{VJ} = 25^{\circ}C$		10	100	μA
				T <sub>vJ</sub> = 150°C		100	1	μA
l <sub>ges</sub>	Gate emitter leakage current	$V_{ce} = 0 V$	$V_{GE} = \pm 20 \text{ V}$				500	nA
V <sub>GE(th)</sub>	Gate emitter threshold voltage	$I_c = 8 \text{ mA}$	$V_{CE} = V_{GE}$	$T_{vJ} = 25^{\circ}C$	5.5		7	V
<b>Q</b> <sub>Gon</sub>	Total gate charge	I <sub>c</sub> = 200 A	$V_{CE} = 600V$	$V_{GE} = \pm 15$ V		630		nC
R <sub>G Int</sub>	Internal gate resistor		. X .					Ω
C <sub>les</sub>	Input capacitance		A.Y			tbd		nF
Coes	Output capacitance	$V_{ce} = 25 V$	$V_{GE} = 0 V$	$T_{vJ} = 25^{\circ}C$		tbd		pF
C <sub>res</sub>	Reverse transfer capacitance	f = 1 MHz				tbd	1	pF
t <sub>d(on)</sub>	Turn-on delay time					100		ns
t,	Current rise time					50	-	ns
t <sub>d(off)</sub>	Turn-off delay time	$V_{G} = 600 V$	I <sub>c</sub> = 200 A			300		ns
t <sub>f</sub>	Current fall time	$R_{g} = 3.9 \Omega$	$V_{GE} = \pm 15 \text{ V}$	$T_{VJ} = 150^{\circ}C$		150	1	ns
E <sub>on</sub>	Turn-on energy per pulse	measured with	h: DMHP 129-12			21	1	mJ
E <sub>off</sub>	Turn-off energy per pulse					19		mJ
RBSOA	Reverse bias safe operation area	$V_{GE}$ = 15 V	$R_{g} = 3.9 \Omega$	$T_{VJ} = 150^{\circ}C$				
				$V_{ce} = 1200 V$			400	Α
SCSOA	Short circuit safe operation area						1	
t <sub>sc</sub>	Short circuit duration	V <sub>CE</sub> = 800 V	$V_{GE} = \pm 15 \text{ V}$	T <sub>vJ</sub> = 150°C			10	μs
I <sub>sc</sub>	Short circuit current	$R_{G} = 3.9 \Omega$	non-repetitive			900		А

## Dimensions (1 mm = 0.0394")



Α	В	С	D	Ε
[mm]	[mm]	[mm]	[mm]	[mm]
18.0	12.47	n/a	n/a	n/a

F	G	Н	1	J
[mm]	[mm]	[mm]	[mm]	[mm]
n/a	n/a	n/a	n/a	n/a